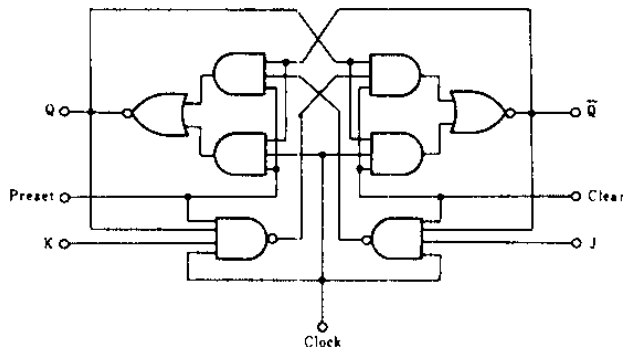
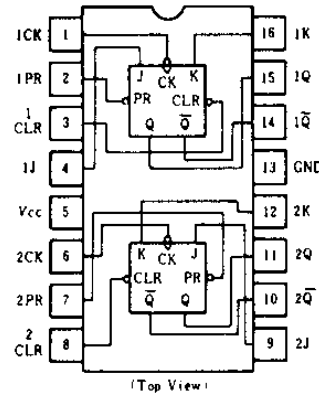


HD74LS76A • Dual J-K Flip-Flops (with Preset and Clear)

■ BLOCK DIAGRAM (1/2)



■ PIN ARRANGEMENT

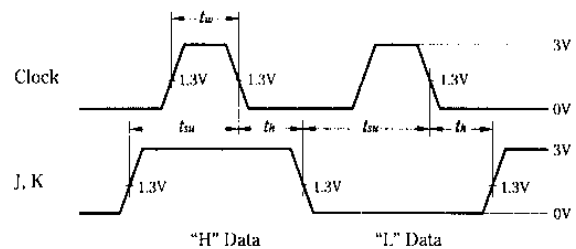


■ RECOMMENDED OPERATING CONDITIONS

Item	Symbol	min	typ	max	Unit
Clock frequency	f_{clock}	0	—	30	MHz
Pulse width	Clock High	20	—	—	ns
	Clear Preset Low	25	—	—	
Setup time	"H" Data	20↓	—	—	ns
	"L" Data	20↓	—	—	
Hold time	t_h	0↓	—	—	ns

Note) ↓; The arrow indicates the falling edge.

■ TIMING DEFINITION



■ ELECTRICAL CHARACTERISTICS ($T_a = -20 \sim +75^\circ\text{C}$)

Item	Symbol	Test Conditions	min	typ*	max	Unit	
Input voltage	V_{IH}		2.0	—	—	V	
	V_{IL}		—	—	0.8	V	
Output voltage	V_{OH}	$V_{CC} = 4.75\text{V}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}, I_{OH} = -400\mu\text{A}$	2.7	—	—	V	
	V_{OL}	$V_{CC} = 4.75\text{V}, V_{IH} = 2\text{V}, V_{IL} = 0.8\text{V}$	$I_{OL} = 8\text{mA}$	—	—	0.5	V
			$I_{OL} = 4\text{mA}$	—	—	0.4	
Input current	J, K	$V_{CC} = 5.25\text{V}, V_I = 2.7\text{V}$	—	—	20	μA	
	Clear		—	—	60		
	Preset		—	—	60		
	Clock		—	—	80		
	J, K	$V_{CC} = 5.25\text{V}, V_I = 0.4\text{V}$	—	—	-0.4	mA	
	Clear		—	—	-0.8		
	Preset		—	—	-0.8		
	Clock		—	—	-0.8		
J, K	$V_{CC} = 5.25\text{V}, V_I = 7\text{V}$	—	—	0.1	mA		
Clear		—	—	0.3			
Preset		—	—	0.3			
Clock		—	—	0.4			
Short-circuit output current	I_{OS}	$V_{CC} = 5.25\text{V}$	-20	—	-100	mA	
Supply current ***	I_{CC}	$V_{CC} = 5.25\text{V}$	—	4	6	mA	
Input clamp voltage	V_{IK}	$V_{CC} = 4.75\text{V}, I_{IN} = -18\text{mA}$	—	—	-1.5	V	

* $V_{CC} = 5\text{V}, T_a = 25^\circ\text{C}$

** I_{IL} should not be measured when preset and clear inputs are low at same time.

*** With all outputs open, I_{CC} is measured with the Q and \bar{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

HD74LS76A

FUNCTION TABLE

Inputs					Outputs	
Preset	Clear	Clock	J	K	Q	\bar{Q}
L	H	×	×	×	H	L
H	L	×	×	×	L	H
L	L	×	×	×	H*	H*
H	H	↓	L	L	Q ₀	\bar{Q} ₀
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	Toggle	
H	H	H	×	×	Q ₀	\bar{Q} ₀

Notes) H; high level, L; low level, X; irrelevant
 ↓; transition from high to low level
 Q₀; level of Q before the indicated steady-state input conditions were established.
 \bar{Q} ₀; complement of Q₀ or level of \bar{Q} before the indicated steady-state input conditions were established.
 Toggle; each output changes to the complement of its previous level on each active transition indicated by ↓.
 *: This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

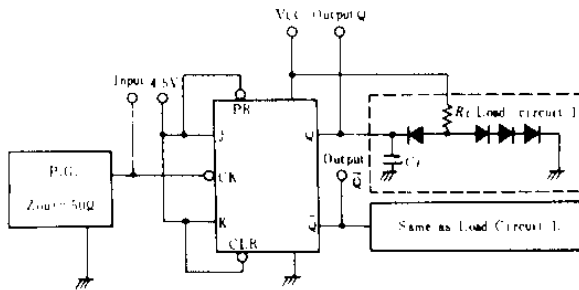
SWITCHING CHARACTERISTICS (V_{CC} = 5V, T_a = 25°C)

Item	Symbol	Inputs	Outputs	Test Conditions	min	typ	max	Unit
Maximum clock frequency	f _{max}			C _L = 15pF, R _L = 2kΩ	30	45	—	MHz
Propagation delay time	t _{PLH}	Clear Preset Clock	Q, \bar{Q}		—	15	20	ns
	t _{PHL}			15	20	ns		

TESTING METHOD

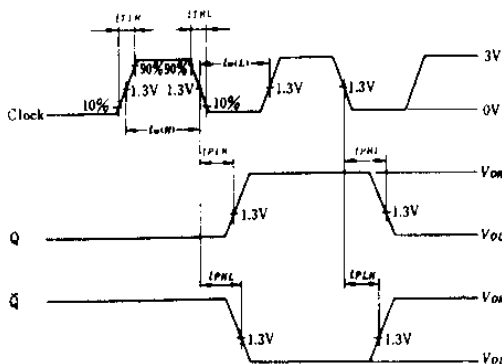
1) Test Circuit

1.1) f_{max}, t_{PLH}, t_{PHL} (Clock → Q, \bar{Q})



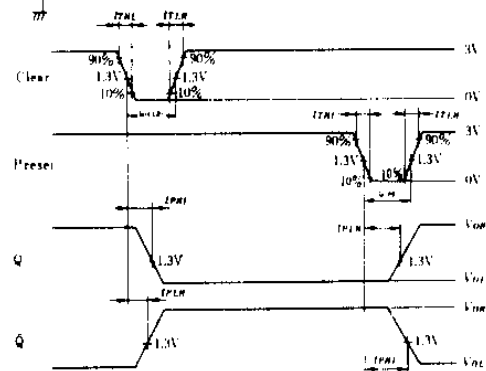
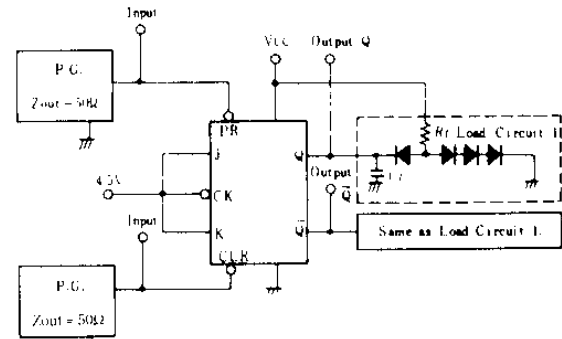
- Notes) 1. Test is put into the each flip-flop
 2. All diodes are 1S2074 (D).
 3. C_L includes probe and jig capacitance.

Waveform



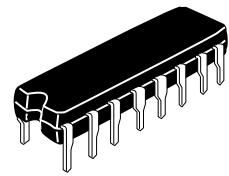
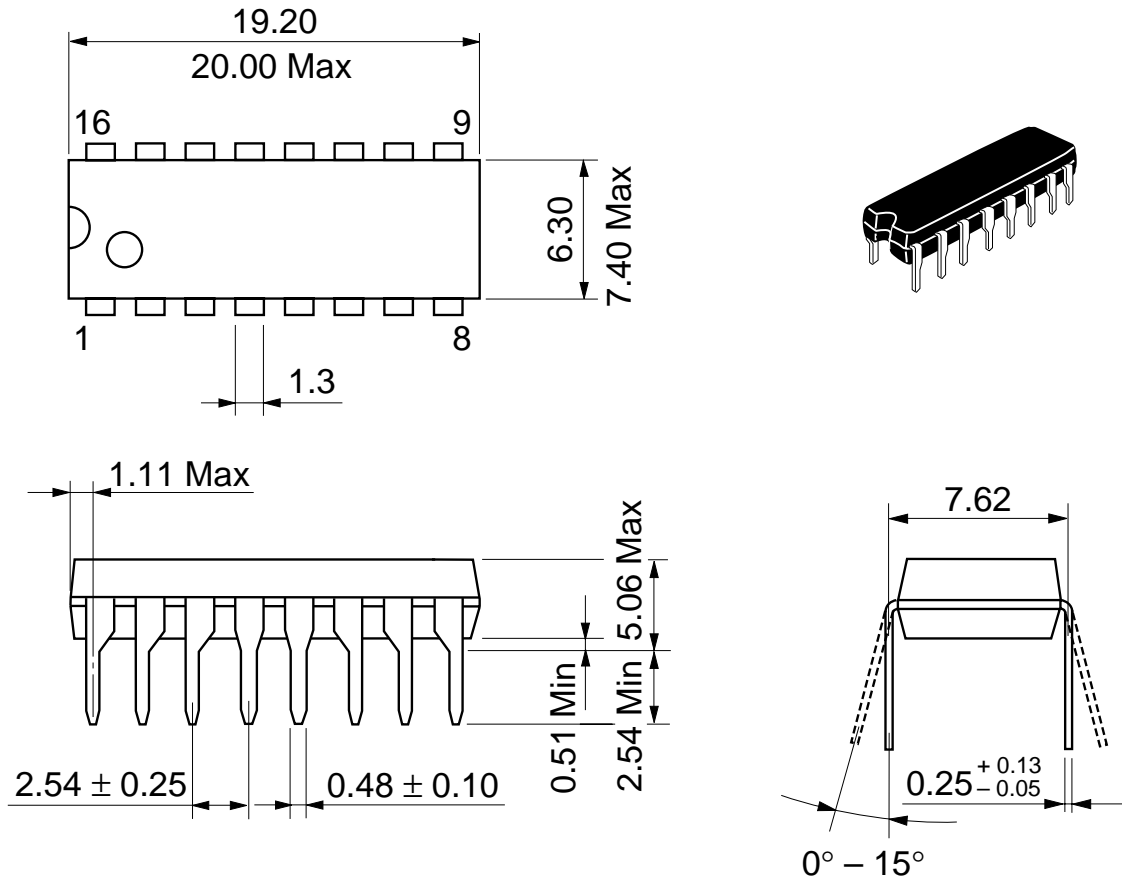
Note) Clock input pulse; t_{TLH} ≤ 15ns,
 t_{TL} ≤ 6ns, PRR = 1MHz, duty
 cycle = 50% and: for f_{max},
 t_{TLH} = t_{TL} ≤ 2.5ns.

1.2) t_{PHL}, t_{PLH} (Clear, Preset → Q, \bar{Q})



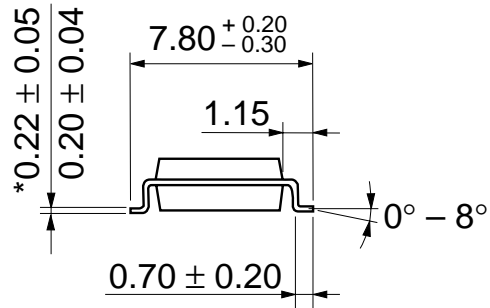
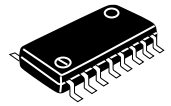
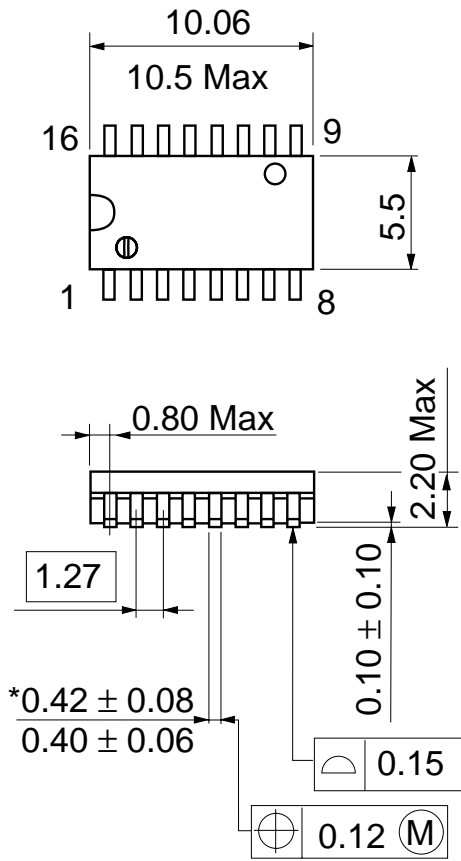
Note) Clear and preset input pulse;
 t_{TLH} ≤ 15ns, t_{TL} ≤ 6ns,
 PRR = 1MHz

Unit: mm



Hitachi Code	DP-16
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	1.07 g

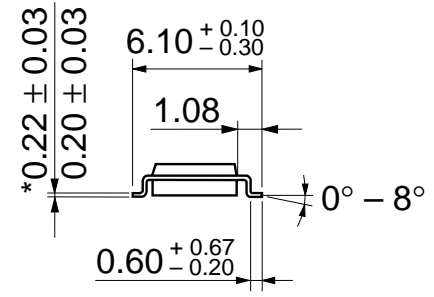
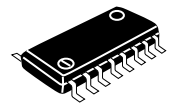
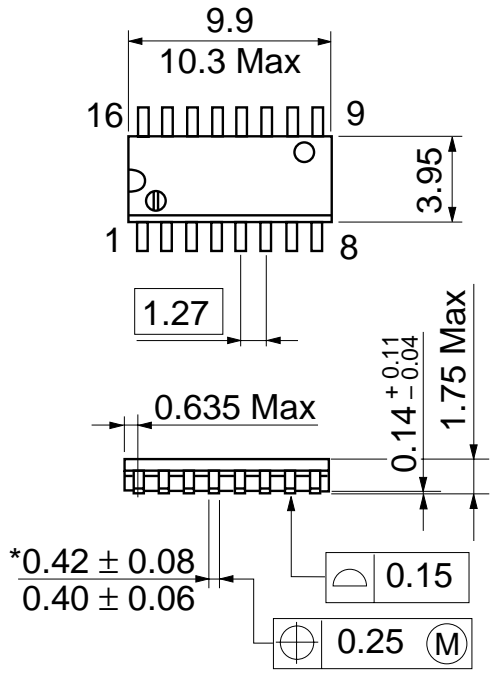
Unit: mm



*Dimension including the plating thickness
 Base material dimension

Hitachi Code	FP-16DA
JEDEC	—
EIAJ	Conforms
Weight (reference value)	0.24 g

Unit: mm



*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-16DN
JEDEC	Conforms
EIAJ	Conforms
Weight (reference value)	0.15 g

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HITACHI

Hitachi, Ltd.

Semiconductor & Integrated Circuits.
Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100-0004, Japan
Tel: Tokyo (03) 3270-2111 Fax: (03) 3270-5109

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For further information write to:

Hitachi Semiconductor
(America) Inc.
179 East Tasman Drive,
San Jose, CA 95134
Tel: <1> (408) 433-1990
Fax: <1> (408) 433-0223

Hitachi Europe GmbH
Electronic components Group
Dornacher StraÙe 3
D-85622 Feldkirchen, Munich
Germany
Tel: <49> (89) 9 9180-0
Fax: <49> (89) 9 29 30 00

Hitachi Europe Ltd.
Electronic Components Group.
Whitebrook Park
Lower Cookham Road
Maidenhead
Berkshire SL6 8YA, United Kingdom
Tel: <44> (1628) 585000
Fax: <44> (1628) 778322

Hitachi Asia Pte. Ltd.
16 Collyer Quay #20-00
Hitachi Tower
Singapore 049318
Tel: 535-2100
Fax: 535-1533

Hitachi Asia Ltd.
Taipei Branch Office
3F, Hung Kuo Building, No.167,
Tun-Hwa North Road, Taipei (105)
Tel: <886> (2) 2718-3666
Fax: <886> (2) 2718-8180

Hitachi Asia (Hong Kong) Ltd.
Group III (Electronic Components)
7/F., North Tower, World Finance Centre,
Harbour City, Canton Road, Tsim Sha Tsui,
Kowloon, Hong Kong
Tel: <852> (2) 735 9218
Fax: <852> (2) 730 0281
Telex: 40815 HITEC HX

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